

# CSE435 Introduction to EDA & Testing - Spring 2022

## Homework Assignment #5

Shao-Hsuan Chu - B073040018

1. (20%) A circuit has the truth table of Table 1. When there is a fault (faults) on the circuit, the faulty truth table becomes Table 2. Try to derive tests to detect the fault (faults).

CD \ AB	AB			
	00	01	11	10
00	1			
01		1	1	
11				1
10			1	1

Table 1

CD \ AB	AB			
	00	01	11	10
00				
01		1	1	
11				
10	1		1	1

Table 2

**Solution:** Compare two truth tables, we can tell the circuit has stuck-at-0 fault at output when input  $\{A, B, C, D\}$  equals  $\{0, 0, 0, 0\}$  or  $\{1, 0, 1, 1\}$ . The circuit also has stuck-at-1 fault at output when the input equals  $\{0, 0, 1, 0\}$ .

**Answers:**  $\{\{0, 0, 0, 0\}, \{1, 0, 1, 1\}, \{0, 0, 1, 0\}\}$

2. (80%) Generate a test for the fault f-sa1 in Figure 1 by the following FOUR methods. Be sure to give the **key steps to show the features of every algorithm**, and also **draw the decision trees** for each case.
- (20%) Use the **Boolean difference method** to derive all the test patterns to detect the fault f-sa1.
  - (20%) Generate a test for the fault f-sa1 by using **D-algorithm**.
  - (20%) Generate a test for the fault f-sa1 by using **9-V Algorithm**.
  - (20%) Generate a test for the fault f-sa1 by using **PODEM algorithm**.

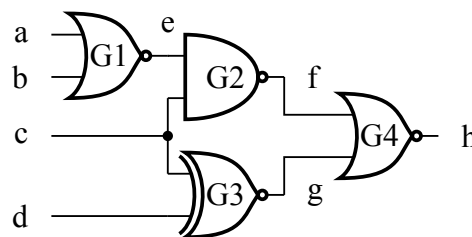


Figure 1